

1.Description

This Power MOSFET is designed to withstand high energy in the avalanche and commutation modes. Designed for low-voltage, high speed switching applications in power supplies, converters, and power motor controls, these devices are particularly well suited for bridge circuits where diode speed and commutating safe operating areas are critical and offer an additional safety margin against unexpected voltage transients.

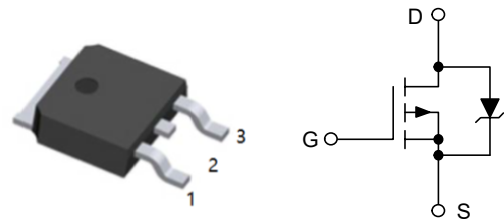
2.Features

- $V_{DS(V)} = -60V$
- $I_D = -20A$
- $R_{DS(ON)} = 53m\Omega$
- Avalanche Energy Specified
- I_{DSS} and $V_{DS(ON)}$ Specified at Elevated Temperature
- Designed for Low-Voltage, High-Speed Switching Applications and to Withstand High Energy in the Avalanche and Commutation Modes

3.Pinning information

Pin	Symbol	Description
1	G	GATE
2	D	DRAIN
3	S	SOURCE

TO-252(DPAK)
top view



4.Absolute Maximum Ratings $T_c = 25^\circ C$

Parameter	Symbol	Rating	Units
Drain-to-Source Voltage	V_{DSS}	-60	V_{dc}
Gate-to-Source Voltage-Continuous	V_{GS}	± 20	V_{dc}
-Non-repetitive ($t_p \leq 10$ ms)	V_{GSM}	± 25	V_{pk}
Drain Current-Continuous @ $T_A = 25^\circ C$	I_D	-12	A_{dc}
-Single Pulse ($t \leq 10$ ms)	I_{DM}	-36	A_{pk}
Total Power Dissipation @ $T_A = 25^\circ C$	P_D	55	W
Storage Temperature Range	T_J, T_{STG}	-55 to 175	$^\circ C$



Single Pulse Drain-to-Source Avalanche Energy-Starting $T_j = 25^\circ\text{C}$ ($V_{DD} = 25\text{Vdc}$, $V_{GS} = 10\text{Vdc}$, Peak $I_L = 12\text{Apk}$, $L = 3.0\text{ mH}$, $R_G = 25\Omega$)	E_{AS}	216	mJ
Thermal Resistance-Junction-to-Case	$R_{\theta JC}$	2.73	$^\circ\text{C/W}$
-Junction-to-Ambient (Note 1)	$R_{\theta JA}$	71.4	$^\circ\text{C/W}$
-Junction-to-Ambient (Note 2)	$R_{\theta JA}$	100	$^\circ\text{C/W}$
Maximum Lead Temperature for Soldering Purposes, 1/8 in. from case for 10 seconds	T_L	260	$^\circ\text{C}$

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

1. When surface mounted to an FR4 board using 1 in pad size (Cu area = 1.127 in²).
2. When surface mounted to an FR4 board using the minimum recommended pad size (Cu area = 0.412 in²)



5. Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
OFF CHARACTERISTICS						
Drain-to-Source Breakdown Voltage (Positive Temperature Coefficient) (Note 3)	$V_{(BR)DSS}$	$V_{GS}=0Vdc, I_D=-0.25mA$	-60			Vdc
				67		mV/°C
Zero Gate Voltage Drain Current	I_{DSS}	$V_{GS}=0Vdc, V_{DS}=-60V, T_J=25^{\circ}C$			-10	μA_{dc}
		$V_{GS}=0Vdc, V_{DS}=-60V, T_J=150^{\circ}C$			-100	μA_{dc}
Gate-Body Leakage Current	I_{GSS}	$V_{GS}=\pm 20Vdc, V_{DS}=0Vdc$			± 100	nAdc
ON CHARACTERISTICS (Note 3)						
Gate Threshold Voltage (Negative Temperature Coefficient)	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=-250\mu A_{dc}$	-1.1	-2	-3	V
Static Drain-Source On-State Resistance	$R_{DS(ON)}$	$V_{GS}=-10Vdc, I_D=-6A_{dc}$		150	170	m Ω
Drain-to-Source On-Voltage	$V_{DS(ON)}$	$V_{GS}=-10Vdc, I_D=-12A_{dc}$		-1.86	-2.6	Vdc
		$V_{GS}=-10Vdc, I_D=-6A_{dc}, T_J=150^{\circ}C$			-2	Vdc
Forward Transconductance	g_{FS}	$V_{DS}=10Vdc, I_D=6A_{dc}$		8		Mhos
DYNAMIC CHARACTERISTICS						
Input Capacitance	C_{iss}	$V_{DS}=-25Vdc, V_{GS}=0Vdc$ $f=1MHz$		500	750	pF
Output Capacitance	C_{oss}			150	250	pF
Reverse Transfer Capacitance	C_{rss}			50	100	pF
SWITCHING CHARACTERISTICS (Notes 3 and 4)						
Turn-On Delay Time	$t_{D(on)}$	$V_{DD}=-30Vdc, I_D=-12A$ $V_{GS}=-10V, R_G=9.1\Omega$		10	20	ns
Rise Time	t_r			45	85	ns
Turn-Off Delay Time	$t_{D(off)}$			26	40	ns
Fall Time	t_f			48	90	ns
Gate Charge	Q_T	$V_{DS}=-48Vdc, V_{GS}=-10Vdc$ $I_D=-12A$		15	30	nC
	Q_{GS}			4		nC
	Q_{GD}			7		nC

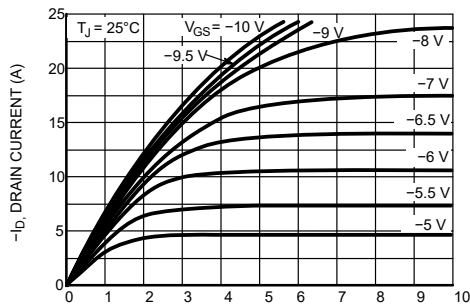


DRAIN-SOURCE DIODE CHARACTERISTICS (Note 3)						
Reverse Recovery Time	V_{SD}	$I_S=12A_{dc}, V_{GS}=0V$		-1.6	-2.5	Vdc
		$I_S=12A_{dc}, V_{GS}=0V, T_J=150^{\circ}C$		-1.3		Vdc
Reverse Recovery Time	t_{rr}	$I_S=12A, dI_S/dt=100 A/\mu s$ $V_{GS}=0 V$		50		ns
	t_a			40		ns
	t_b			10		ns
Reverse Recovery Stored Charge	Q_{rr}			0.1		μC

3. Indicates Pulse Test: Pulse Width $\leq 300 \mu s$, Duty Cycle $\leq 2\%$.
4. Switching characteristics are independent of operating junction temperature.

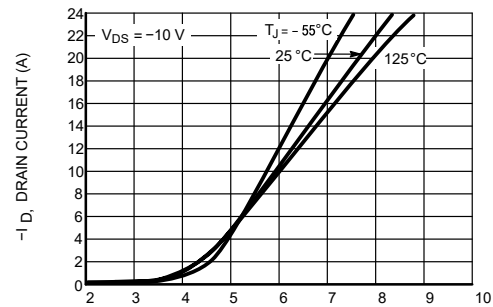


6.1 Typical Characteristics



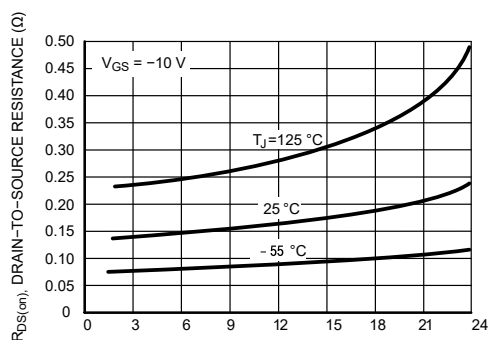
$-V_{DS}$, DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 1: On-Region Characteristics



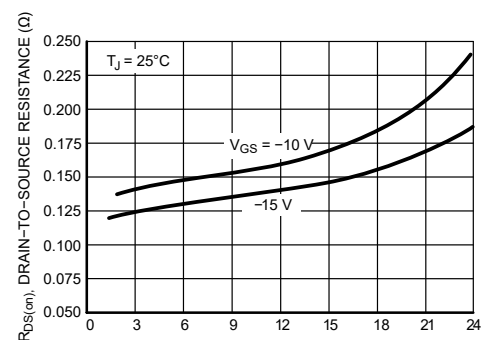
$-V_{GS}$, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 2: Transfer Characteristics



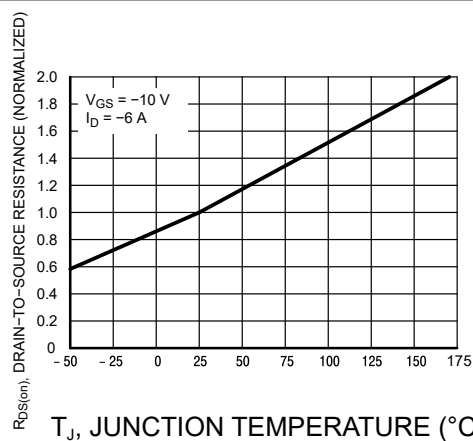
$-I_D$, DRAIN CURRENT (AMPS)

Figure 3: On-Resistance versus Drain Current and Temperature



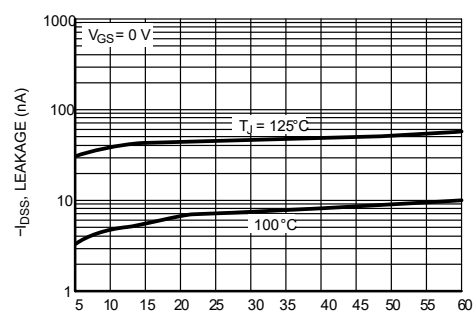
$-I_D$, DRAIN CURRENT (AMPS)

Figure 4: On-Resistance versus Drain Current and Gate Voltage



T_J , JUNCTION TEMPERATURE (°C)

Figure 5: On-Resistance Variation with Temperature



$-V_{DS}$, DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 6: Drain-To-Source Leakage Current versus Voltage



6.2 Typical Characteristics

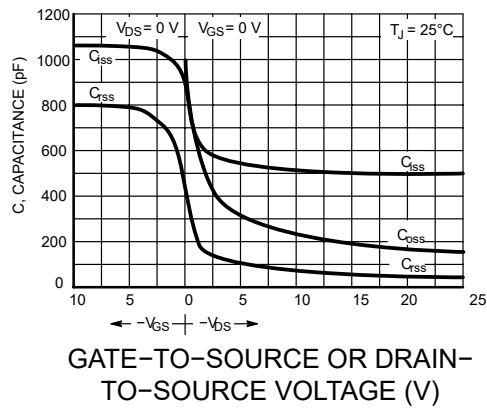


Figure 7: Capacitance Variation

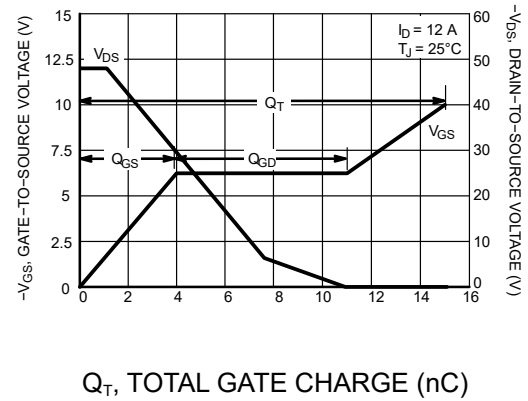


Figure 8: Gate-To-Source and Drain-To-Source Voltage versus Total Charge

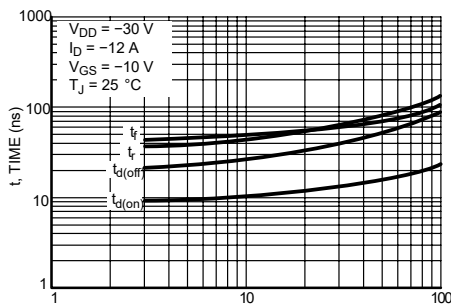


Figure 9: Resistive Switching Time Variation versus Gate Resistance

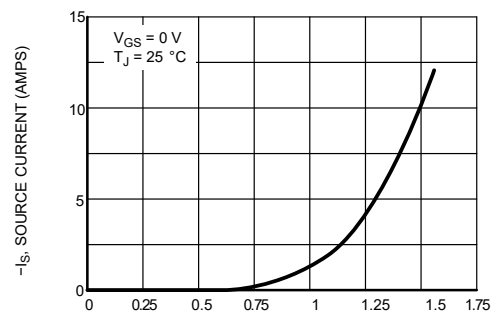


Figure 10: Diode Forward Voltage versus Current

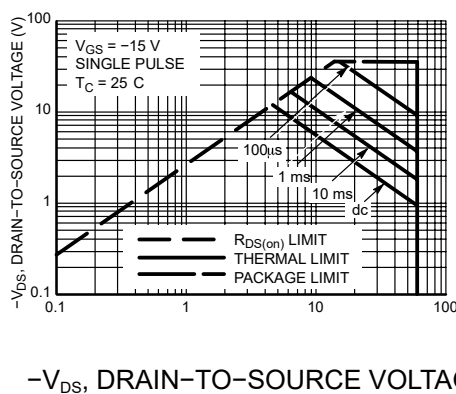


Figure 11: Maximum Rated Forward Biased Safe Operating Area

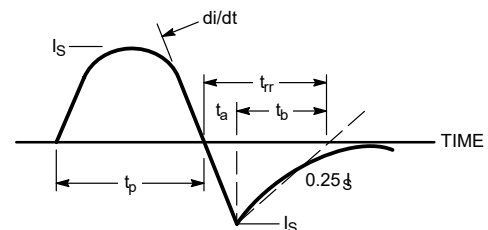


Figure 12: Diode Reverse Recovery Waveform



6.3 Typical Characteristics

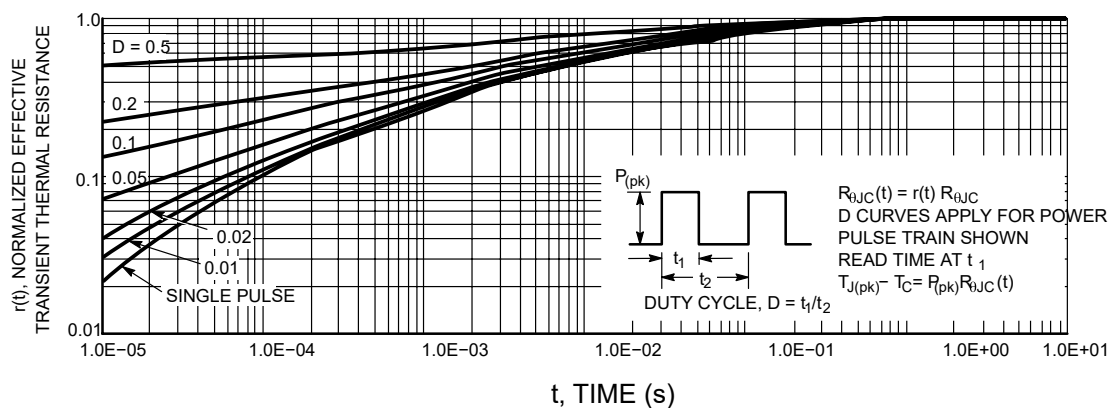
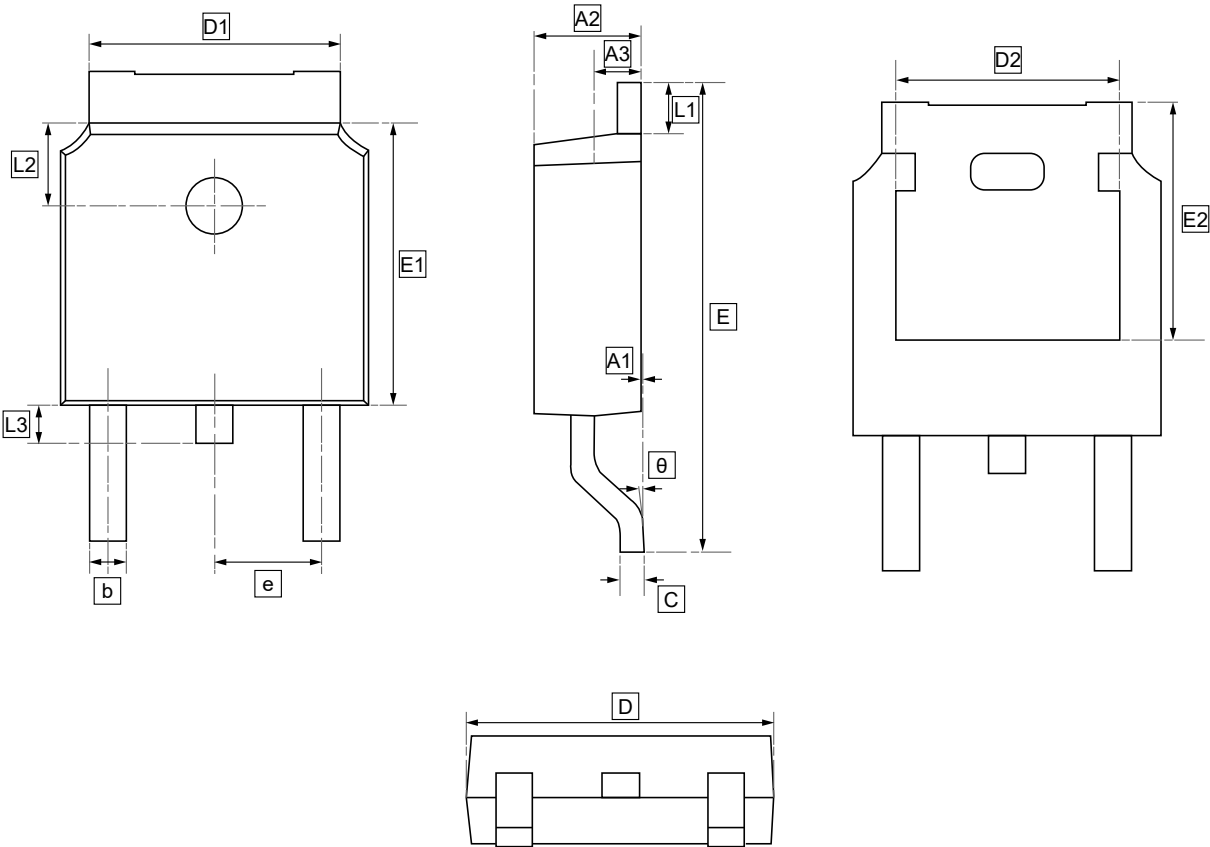


Fig 13: Thermal Response



7.TO-252 Package Outline Dimensions

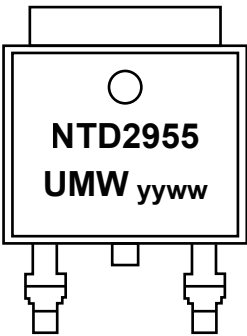


DIMENSIONS (mm are the original dimensions)

Symbol	A1	A2	A3	b	c	D	D1	D2	E	E1	E2	e	L1	L2	L3	θ
Min	0.00	2.18	0.90	0.65	0.46	6.35	4.95	4.32	9.40	5.97	5.21	2.286 BSC	0.89	1.70	0.60	0.00
Max	0.13	2.39	1.10	0.85	0.61	6.73	5.46	4.90	10.41	6.22	5.38		1.27	1.90	1.00	8.00



8.Ordering information



yy: Year Code
ww: Week Code

Order Code	Package	Base QTY	Delivery Mode
UMW NTD2955T4G	TO-252	2500	Tape and reel



9.Disclaimer

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